

Search Notes

Application/Control No.

10/757,877

Examiner

Paul D. Kim

Applicant(s)/Patent under
Reexamination

FEIST ET AL.

Art Unit

3729

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|---|-----------|----------|
| 29 | 592.1 602.1 603.13 604 856 858 | 8/15/2005 | PK |
| 428 | 64.2-64.4 | | |
| | 694 | | |
| 427 | 127 162 | | |
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INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|-----------|------|
| Reviewed Parent Application 09/846,888 US PAT. 6,715,200 | 8/15/2005 | PK |
| Text Search EAST/NPL (IEEE) | 8/15/2005 | PK |
| Updated Text Search EAST | 4/19/2006 | PK |
| Updated Text Search EAST | 8/22/2006 | PK |
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